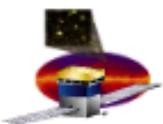


Mini-Tower test results

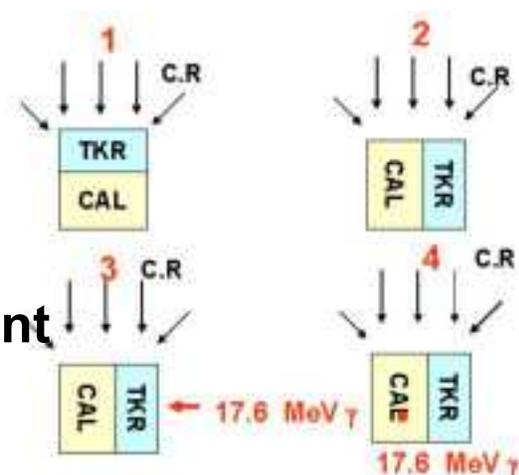
Luca Latronico
INFN Pisa
for the TKR subsystem

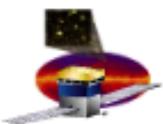
GLAST International Collaboration Meeting
Accademia Nazionale dei Lincei
Roma 15-18 September 2003



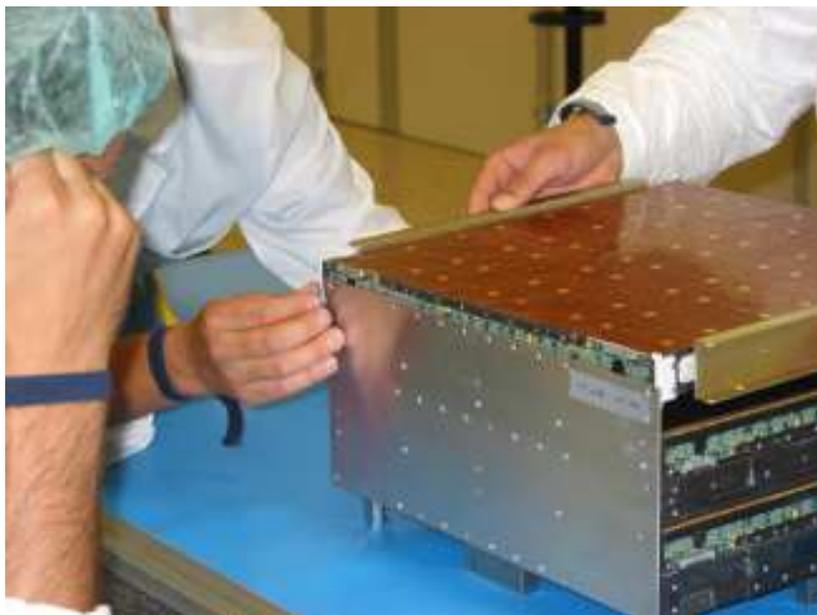
Motivations

- First complete working prototype of flight-like hardware
- 6 Si-layers – 5 trays – minimal configuration for L1T
- Test specific TKR hardware components and assembly strategies:
 - flight Si-Ladders assembly and test
 - mechanical Trays assembly
 - MCMs (GTFE/GTRC tests), assembly onto trays, bonding
 - flex cables
 - tower sidewalls and assembly tools
- Test ELX/DAQ components
- Develop EGSE TKR test suite to test, qualify, operate a tower before delivery to I&T
- Develop documentation templates for efficient hands-off to I&T
- Support I&T during integration with CAL
- Data taking with CR and 17MeV VdG gamma





History



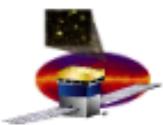
First version of minitower built last february/march

Main problems to be addressed

- **MCM:**
 - **instabilities in the GTFE chip required fine-tuning of the low voltage**
 - **bad pitch adapter (too small pads, not flat surface)**
 - **bad bias HV insulation**
- **Flex cables and connectors to MCM**

Trays were shipped back to INFN and refurbished with new electronics:

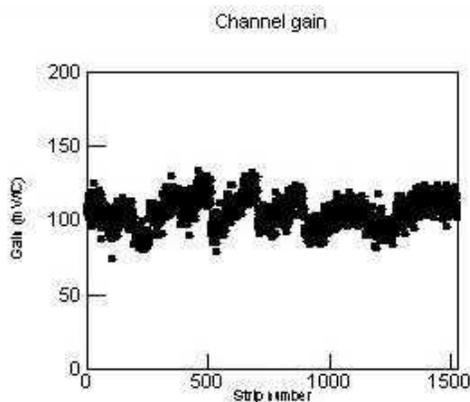
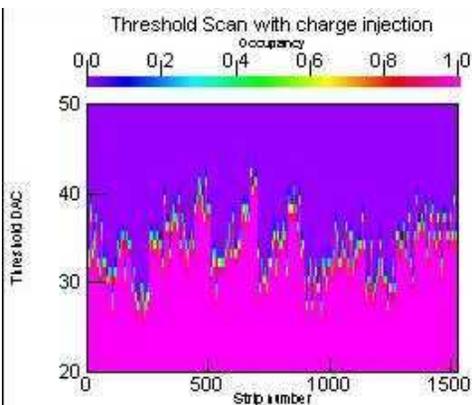
- **MCM:**
 - **new GTFE chip (G3)**
 - **improved pitch adapter**
 - **HV insulation improved with insertion of a Kapton layer**
- **New flex cables and connectors**



Preliminary tests on MCMs

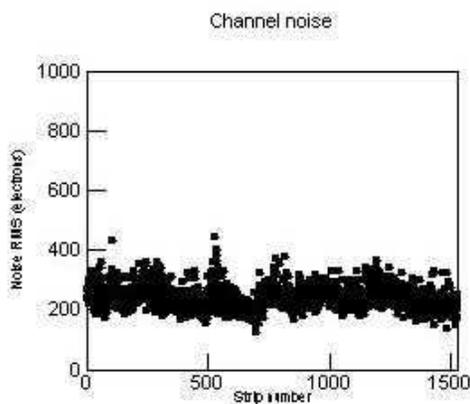
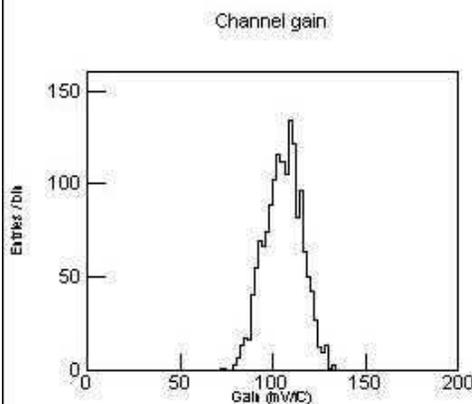
Functional tests from UCSC repeated in Pisa on all bare MCMs

- ✓ GTFE /GTRC register testing
- ✓ Load all possible layer configurations and read few events
- ✓ Inject charge in all channels and look for noisy or dead channels (1 dead ch found)

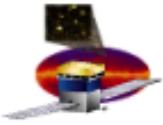


occupancy scan vs threshold

Gain is threshold giving 50% occupancy divided injected charge

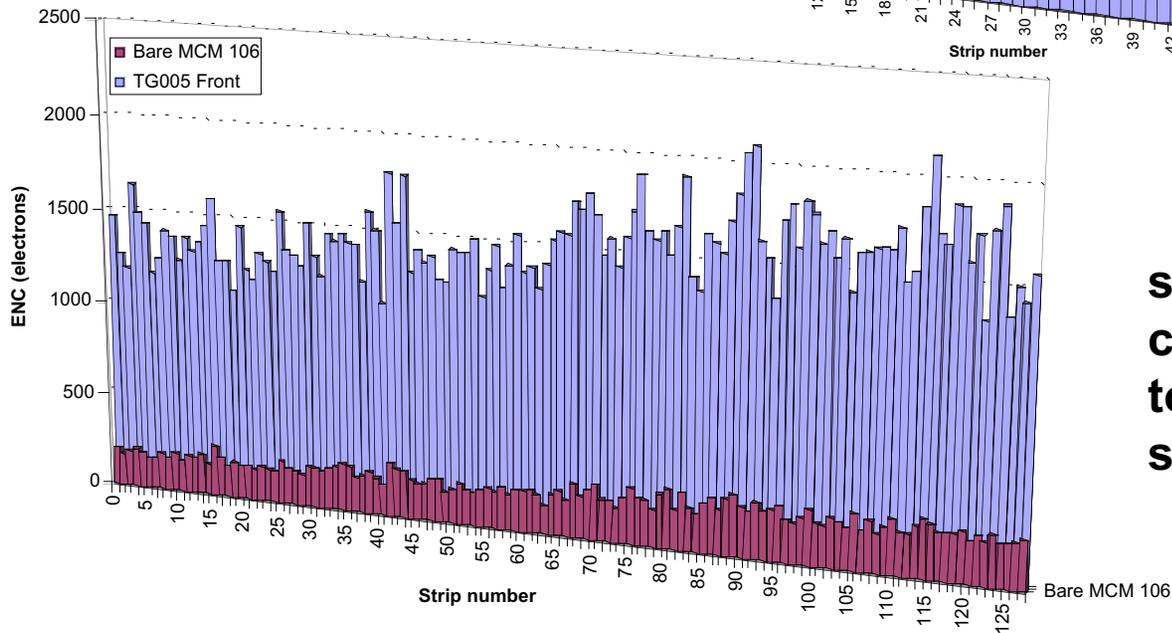
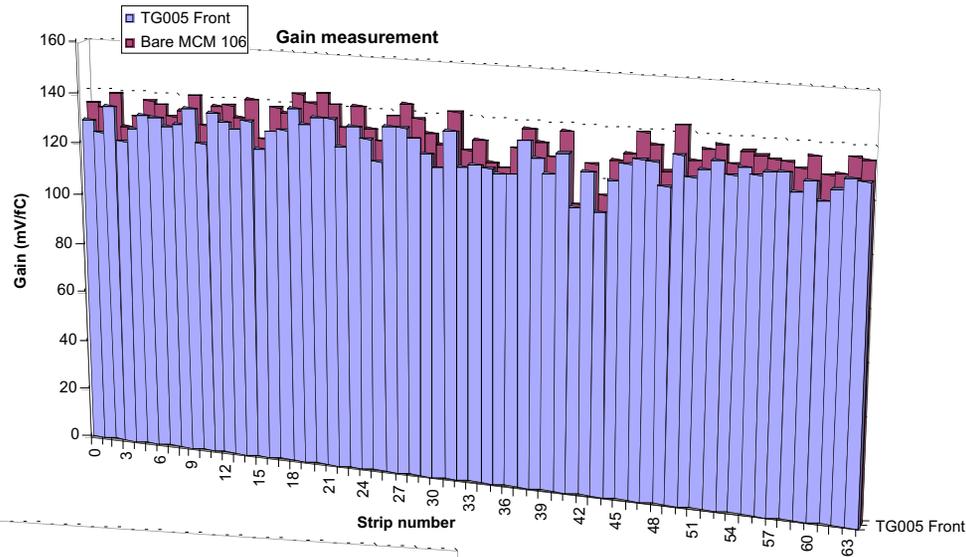


Noise is width of curve

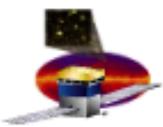


Gain and noise measurement with strips connected

gain does not change



strip noise dominated by capacitive load – reliable tool for disconnected strip search

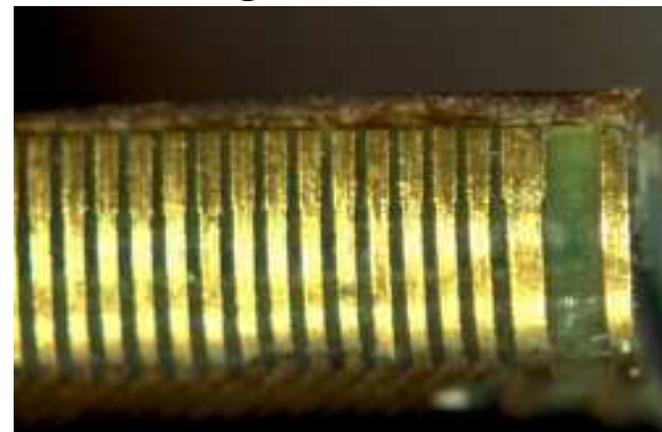
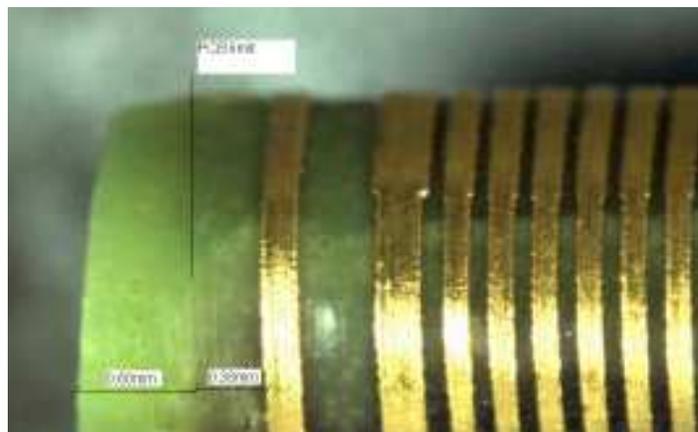


Still missing channels for pitch adapter problems

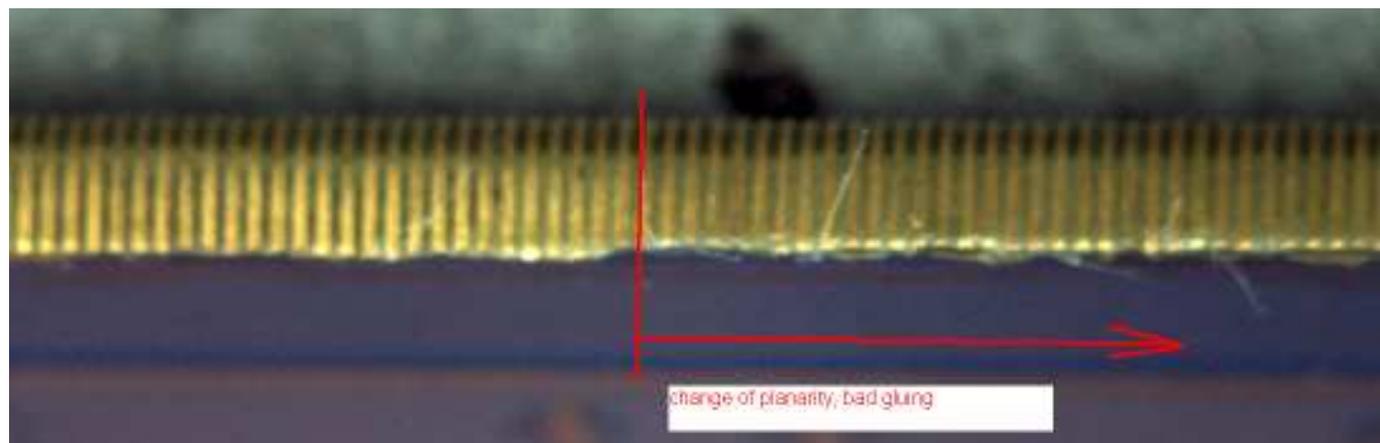
left side

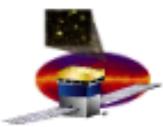
right side

tracks shift



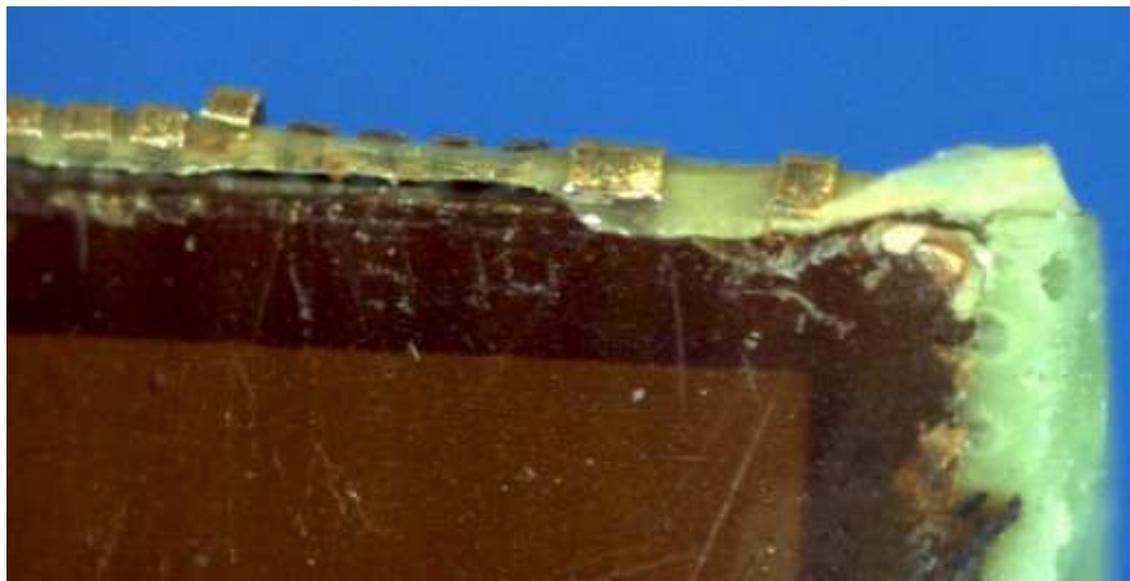
Bad gluing and planarity





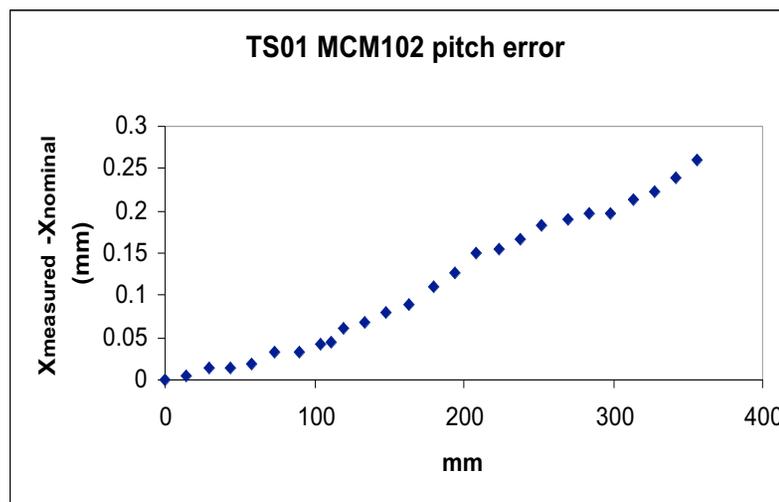
Still missing channels for pitch adapter problems

The HV, GND and some channels lines are wrapped around the PCB edge, preventing bonding



Wrong pitch

- 191 missing wire-bonds to strips
- had to give up redundancy of bias HV connections on border ladders



Minitower construction

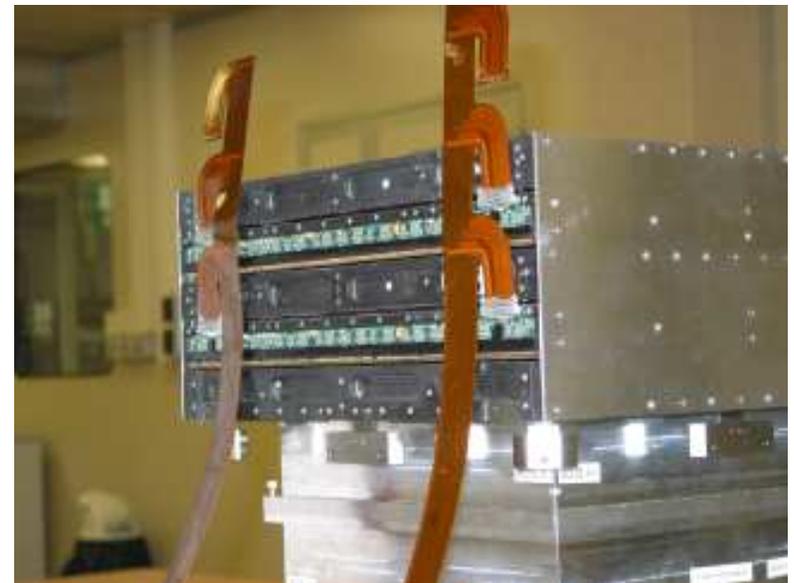
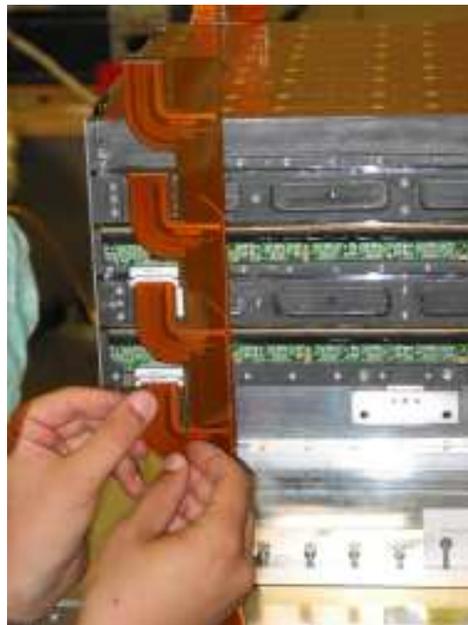


Stacking the trays - sidewalls are reference and support

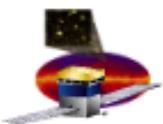


Complete the stack

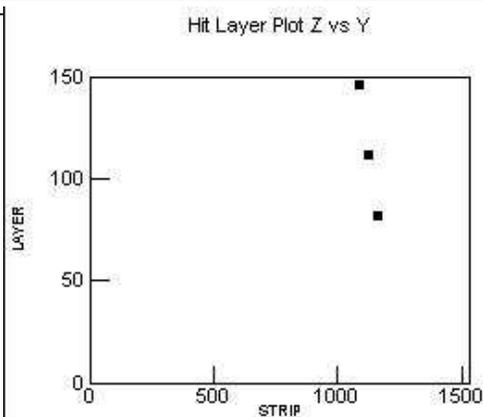
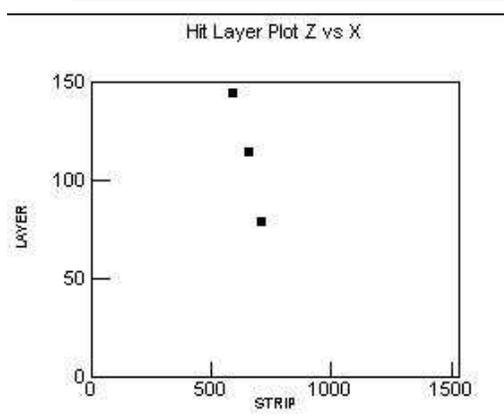
Cabling each side after opening its sidewall



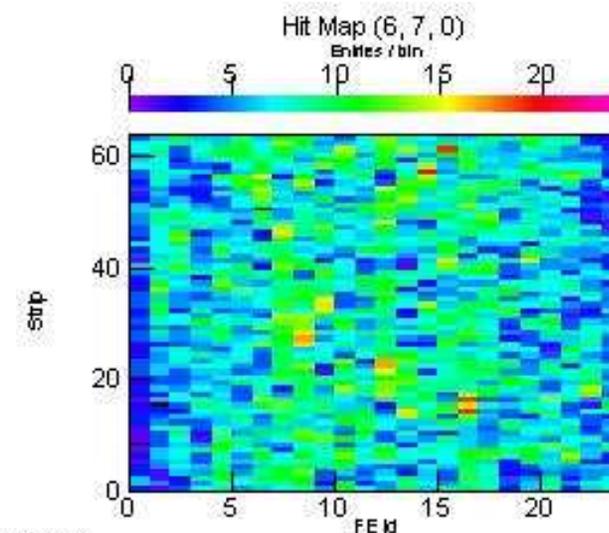
Complete open structure



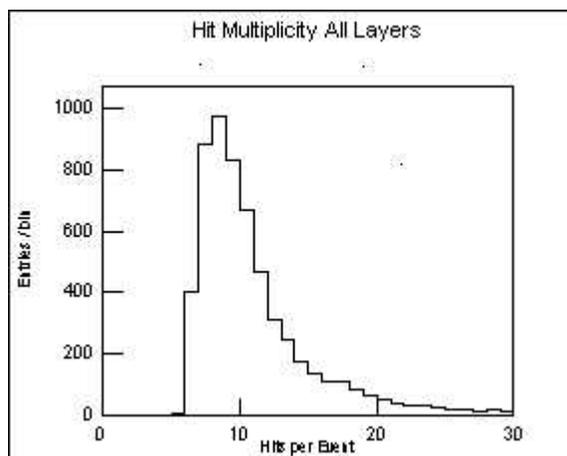
Just 2 hours later real cosmic events start flowing



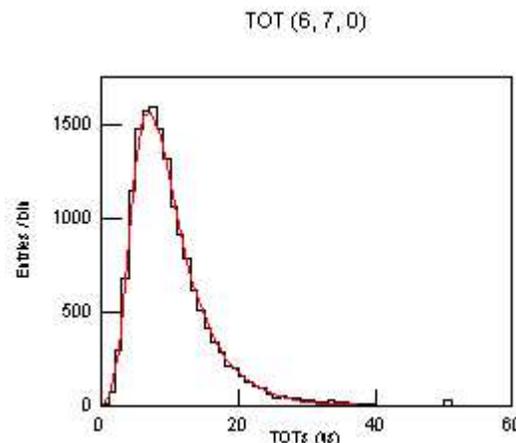
tracks



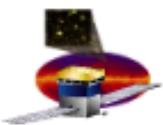
hitmaps



Hit multiplicity



Time Over Threshold



Noisy strip search

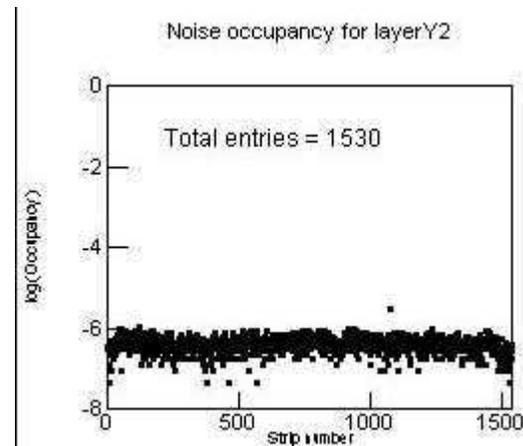
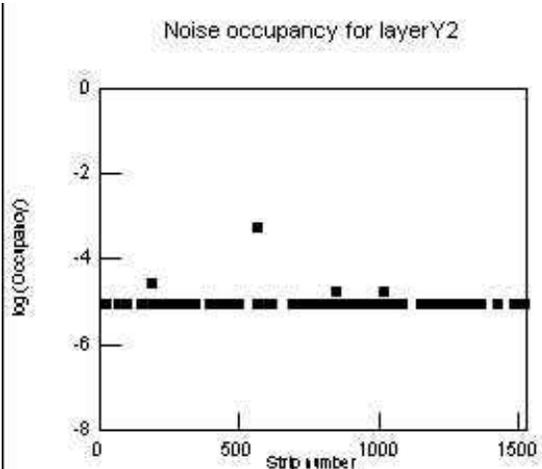
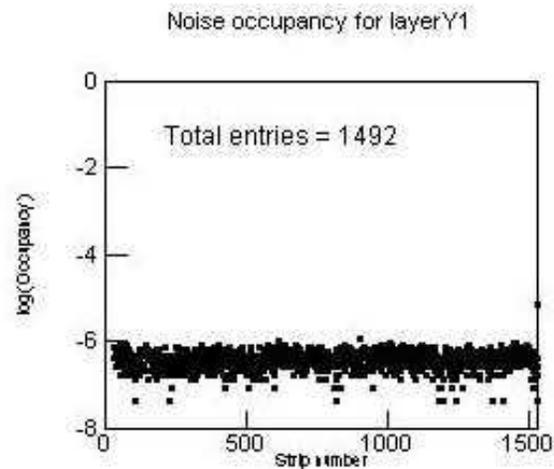
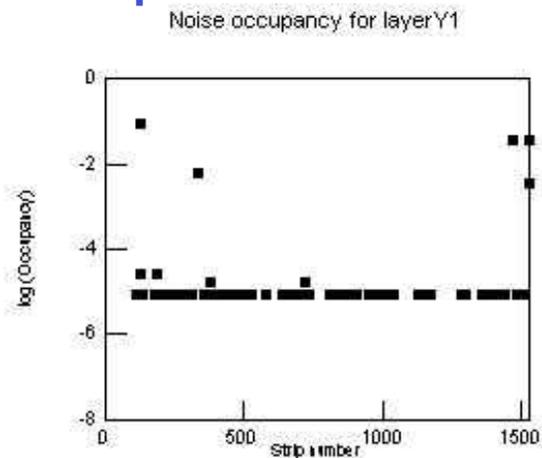
Strip Occupancy

low statistics

Occupancy < 10^{-4}

(LAT-SS-17-5 TKR Level III specs)

13 strips masked



Layer noise occupancy

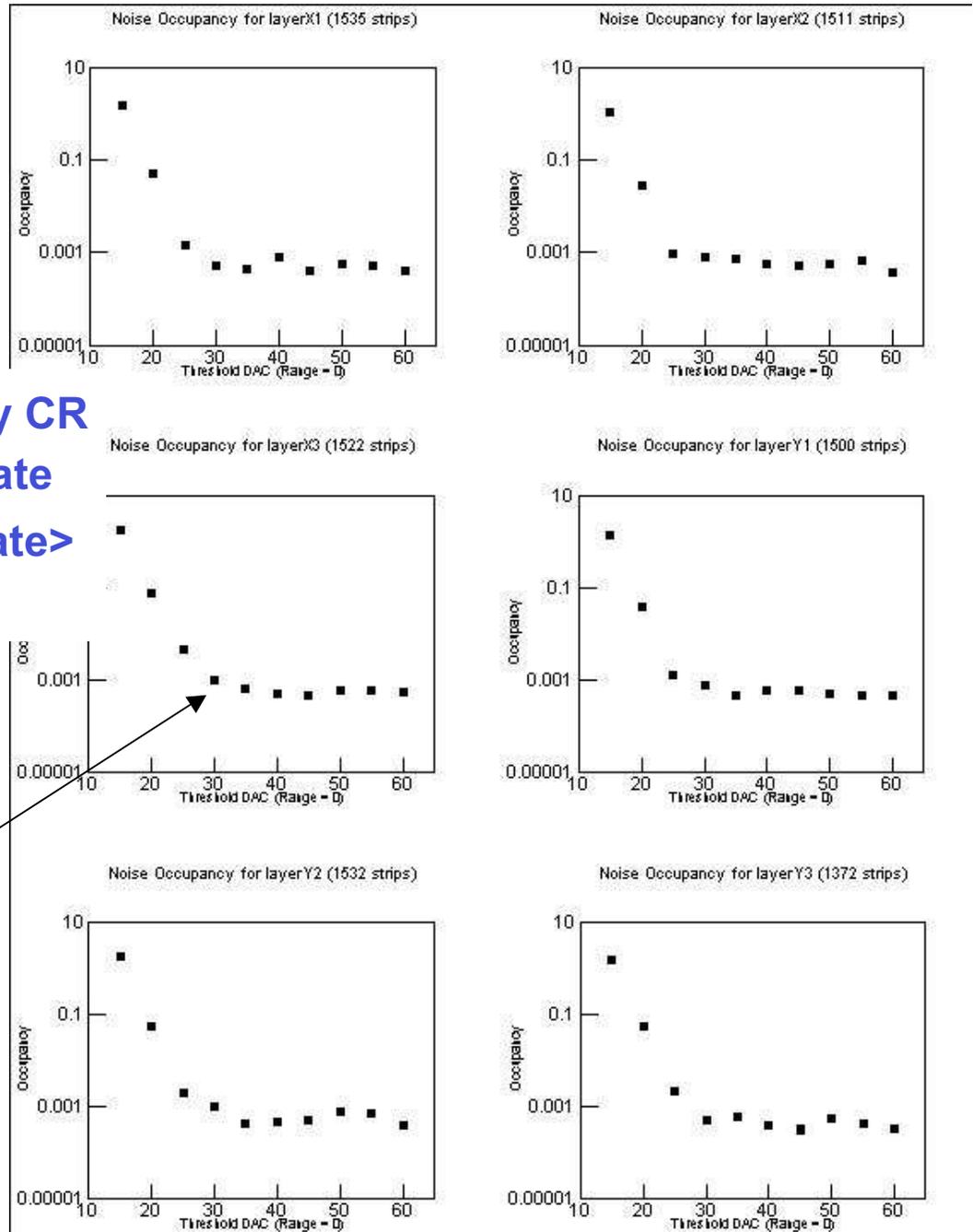
Residual occupancy dominated by CR

CR occupancy \approx CR accidental rate

$\langle \text{ToT} \rangle \langle \text{cluster-size} \rangle \langle \text{CR trigger rate} \rangle$

$$\approx 10 \mu\text{s} * 2 * 30\text{Hz} \approx 6 * 10^{-4}$$

$\approx 1/4$ MIP



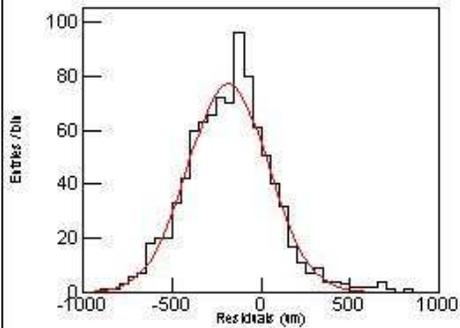
Spatial resolution

layer	Exp STDEV (um)	Meas STDEV (um)	Meas AVG (um)
X1	250	225	-185
X2	115	105	85
X3	210	195	-160
Y1	210	240	-64
Y2	115	135	35
Y3	250	275	-75

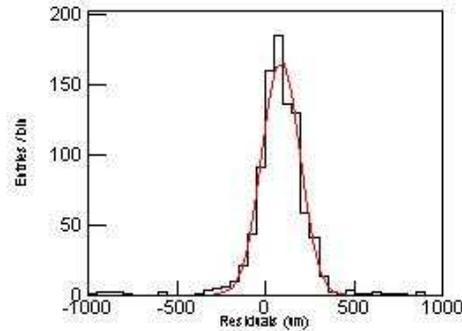
Alignment

Ratio	Expected value	Measured value
mean(X2)/mean(X1)	0.46	0.46
mean(X2)/mean(X3)	0.54	0.53
mean(Y2)/mean(Y1)	0.54	0.55
mean(Y2)/mean(Y3)	0.46	0.48

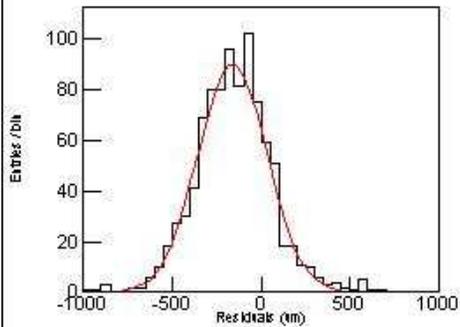
Residuals distribution for layerX1



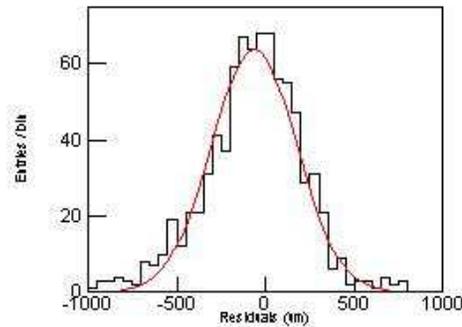
Residuals distribution for layerX2



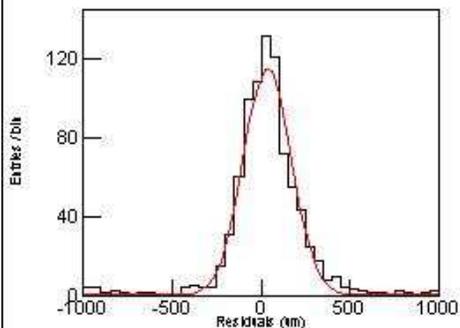
Residuals distribution for layerX3



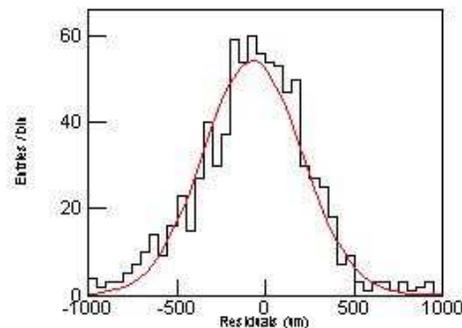
Residuals distribution for layerY1



Residuals distribution for layerY2



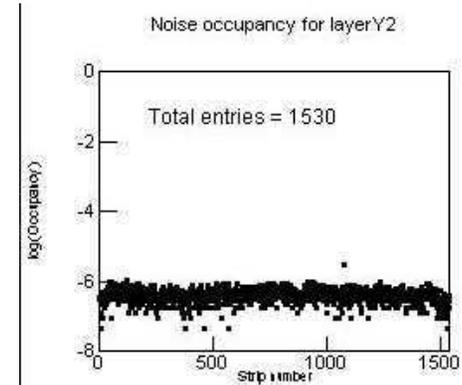
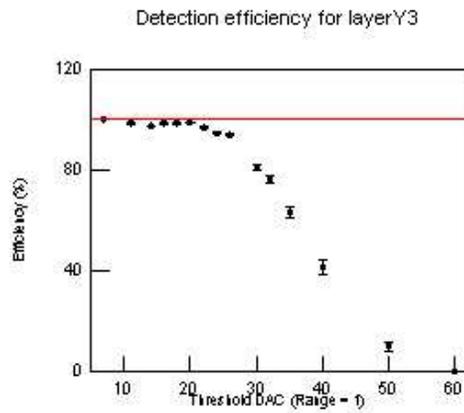
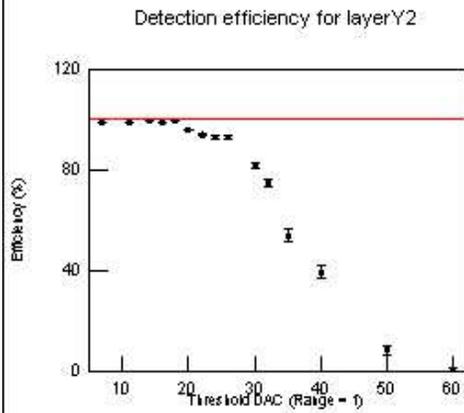
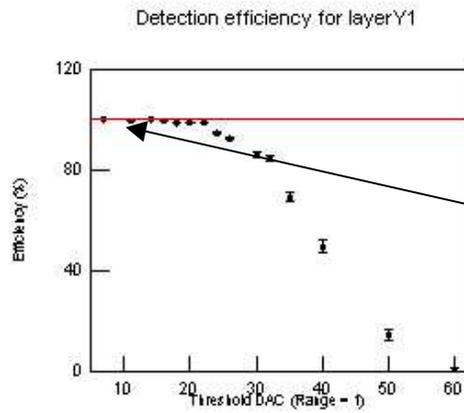
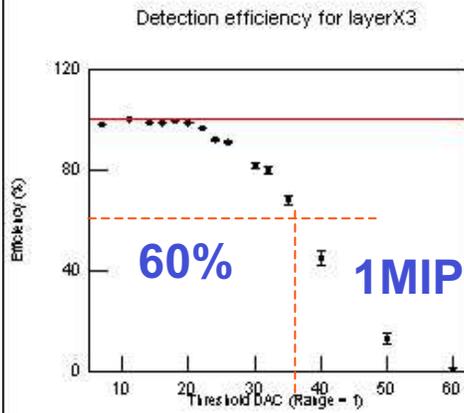
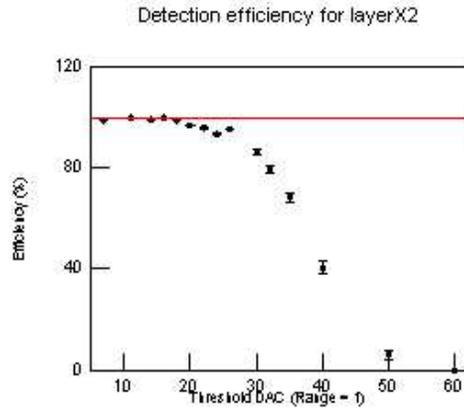
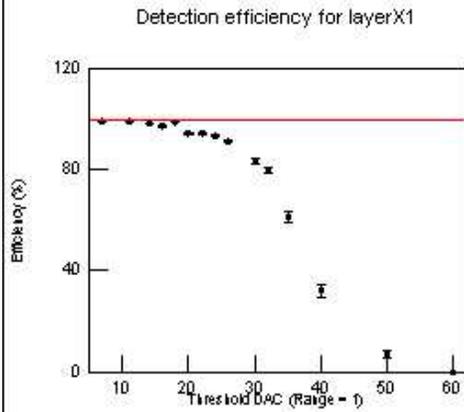
Residuals distribution for layerY3



Detection efficiency

Full efficiency plateau up to \approx 1 MIP

Occupancy @ beginning of efficiency plateau is already as low as 10^{-7} (mainly cosmics)



Occupancy @ DAC Threshold = 10

Light leak from the top

X3 top layer

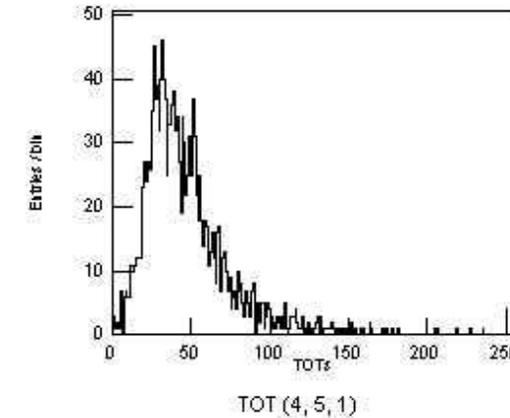
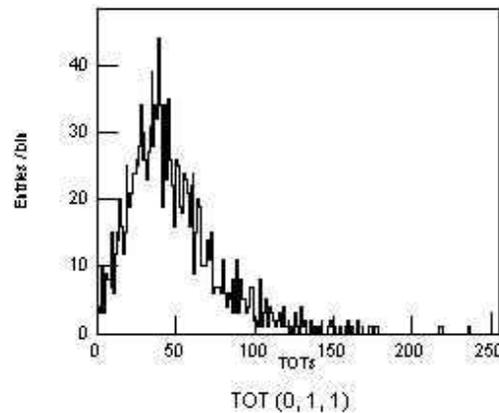
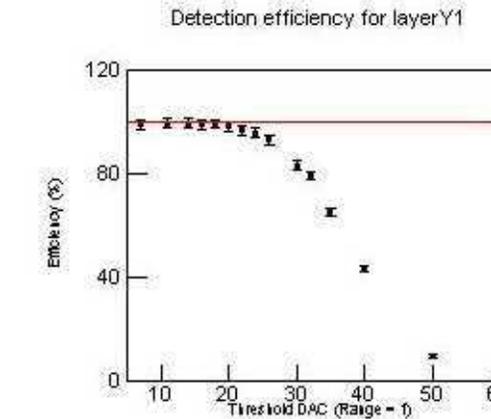
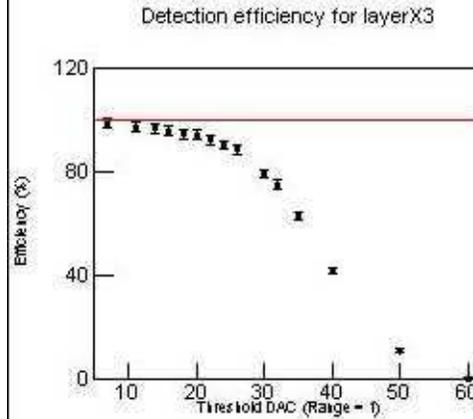
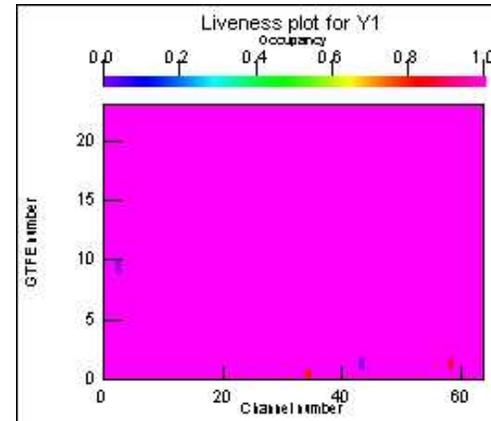
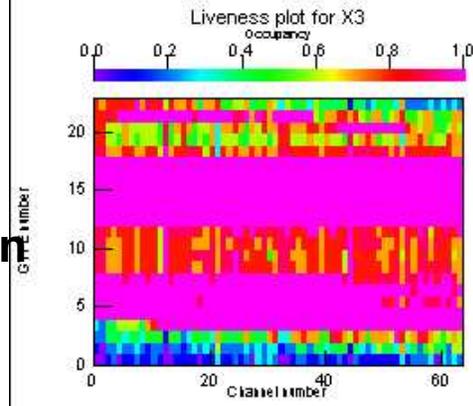
Y1 internal layer

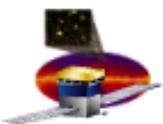
Charge injection

Sidewall could not be tightened for a thermistor out of place on a cable

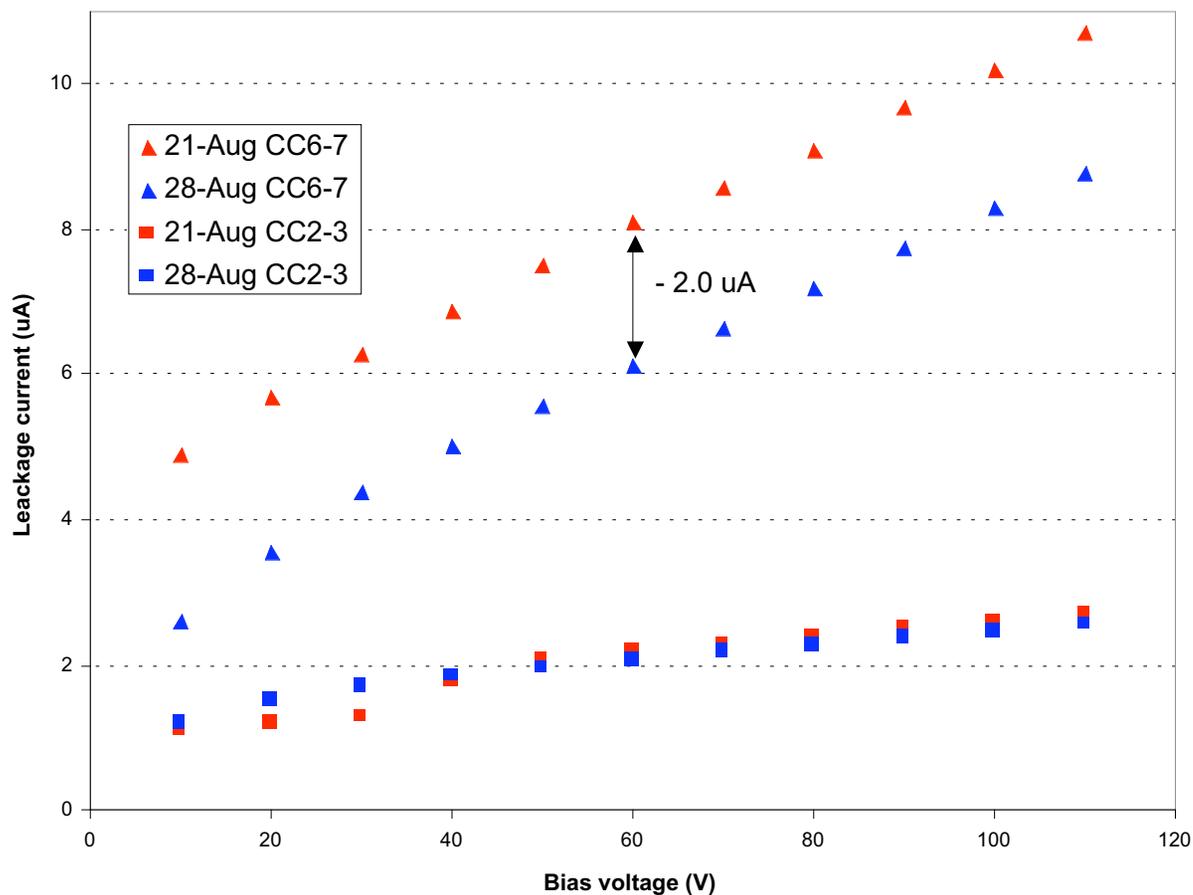
efficiency

Pulse height

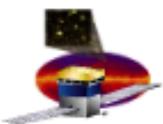




Light leak and leakage current



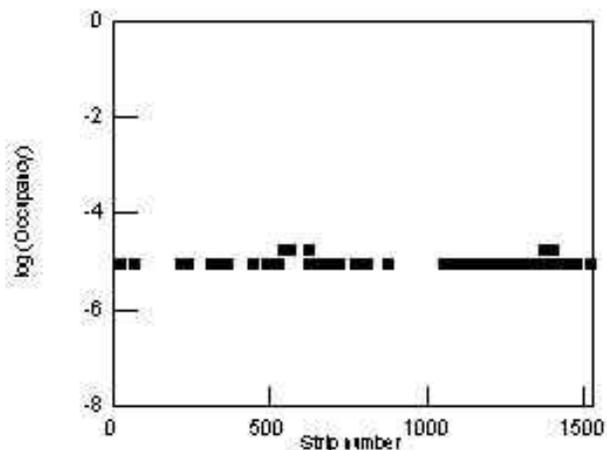
**CC with top layer
see non-negligible
current decrease**



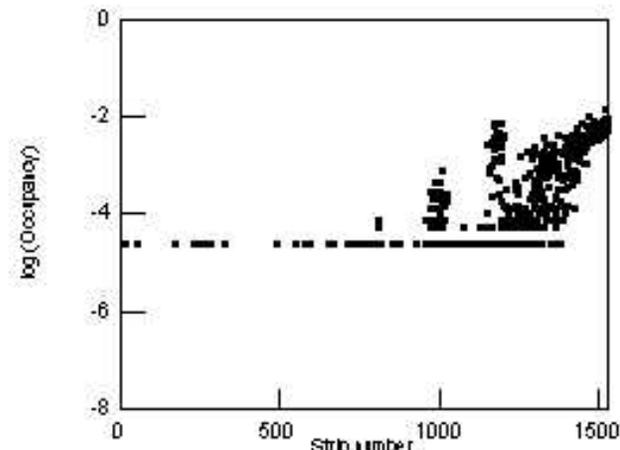
Bad HV connection on border ladder

Border HV line not bonded for pitch adapter and bias circuit inconsistency
Inner line interrupted on MCM side
Repaired with drop of conductive glue

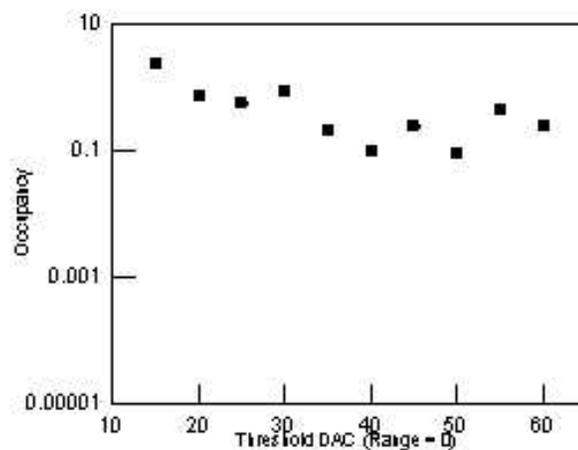
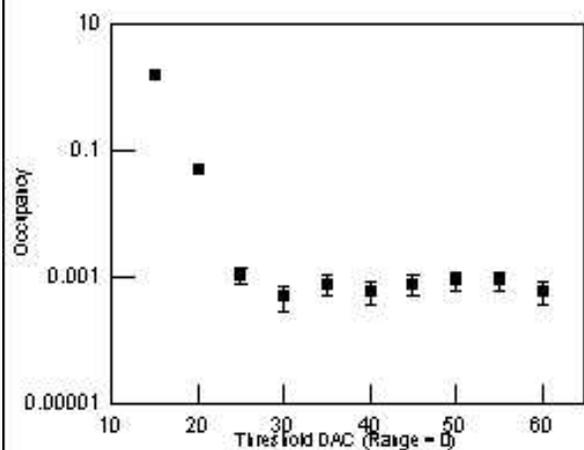
Noise occupancy for layerX1

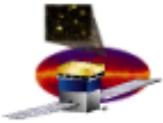


Noise occupancy for layerX2



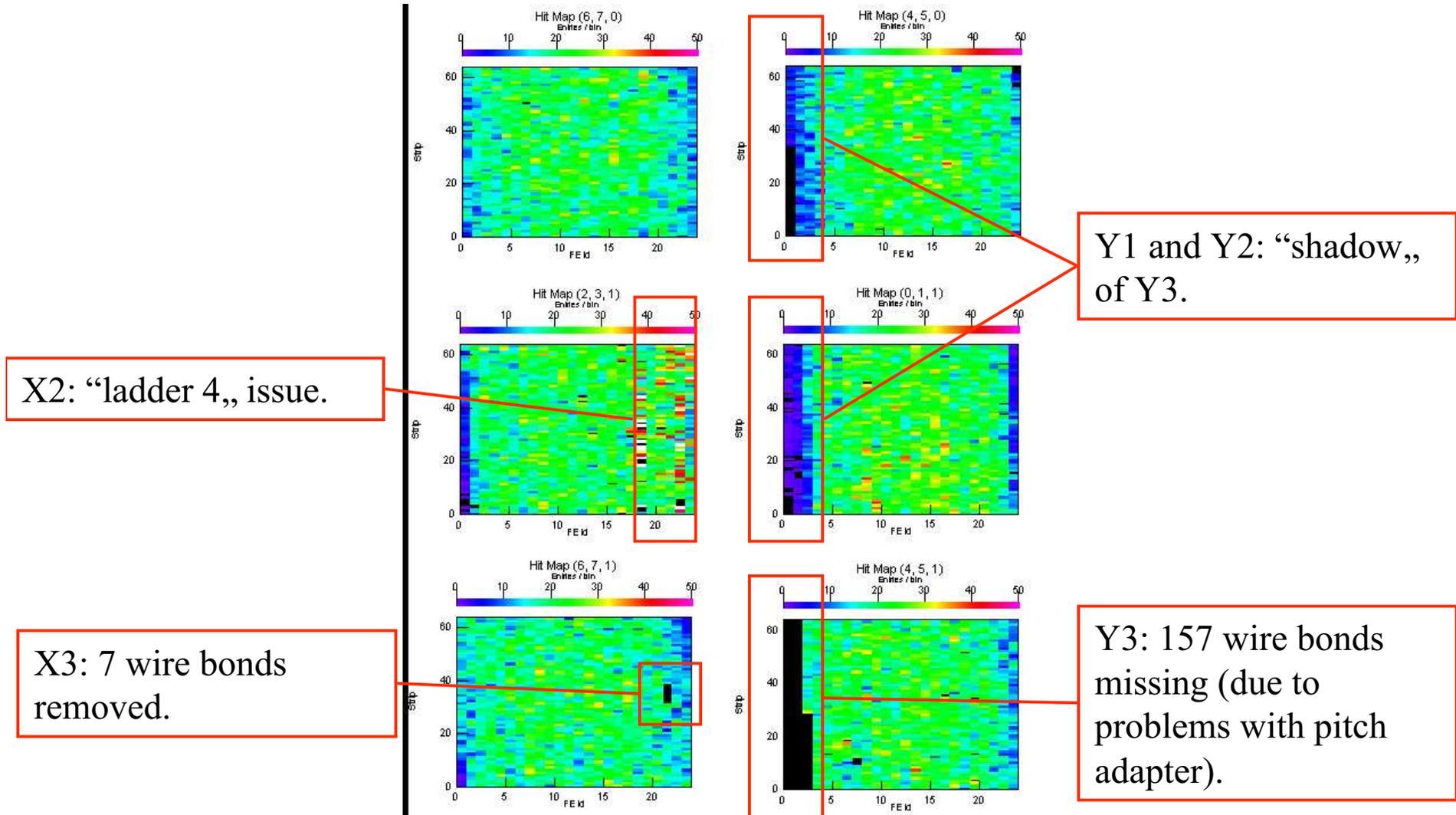
Noise Occupancy for layerX2

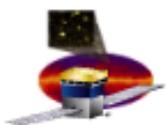




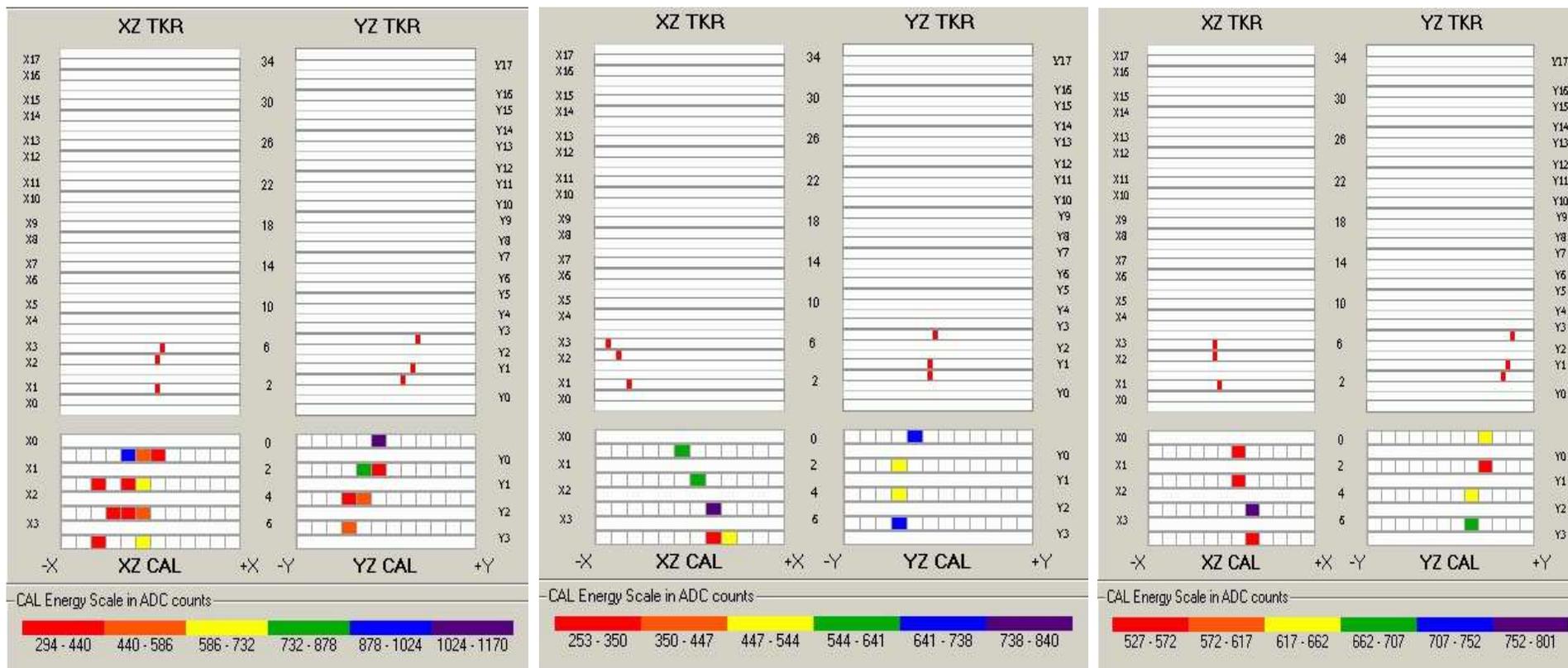
Cosmics - hitmaps

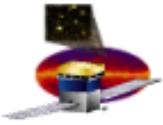
Threshold = 30 DAC, range 0, 13 strips masked. ~ 15000 events collected.





Real CR events from the integrated system



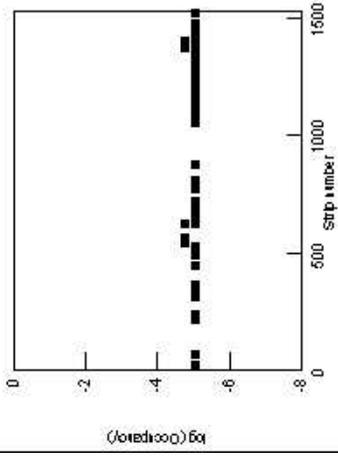


Conclusions

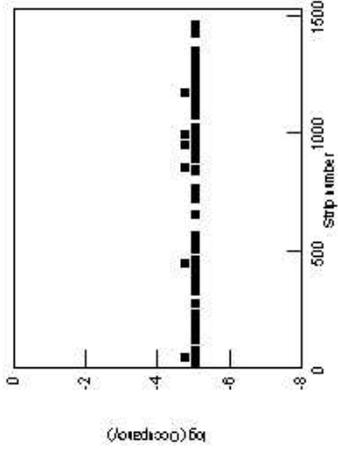
- TKR Minitower refurbished in one week
- TKR Minitower completely characterized before delivery
- Met specs in terms of efficiency, occupancy
- TKR Minitower delivered to I&T according to schedule
- Integration with CAL at SLAC
- Still problems in mechanics of pitch-adapter (2% channels could not be bonded)
- Residual problems in pitch adapter alignment and MCMs bias lines + inconsistencies with older bias circuit induced bias problems in 2 border ladders
- Still read-out problems (time-out errors) in few events ($\approx 1/1000$)

find more at <http://glastserver.pi.infn.it/glast>

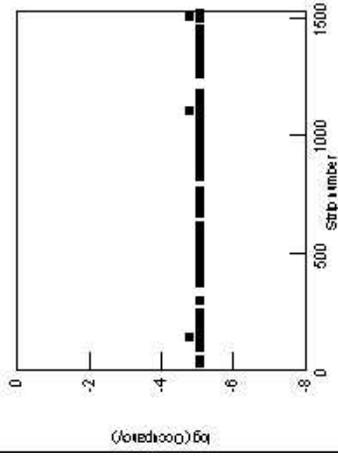
Noise occupancy for layerX1



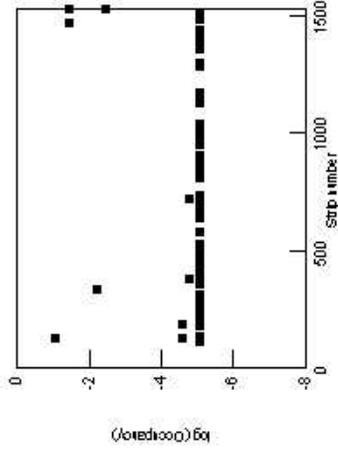
Noise occupancy for layerX2



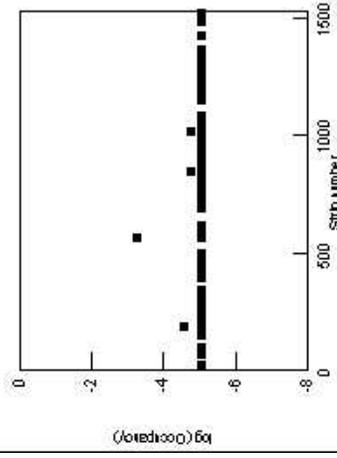
Noise occupancy for layerX3



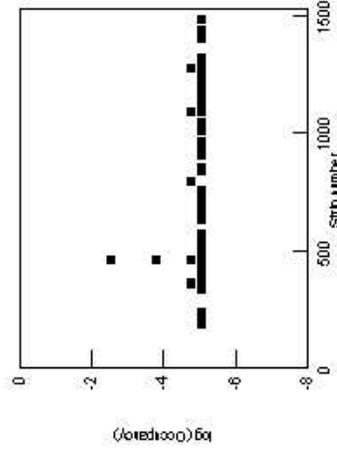
Noise occupancy for layerY1



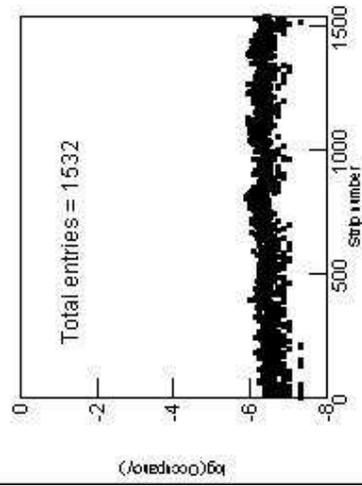
Noise occupancy for layerY2



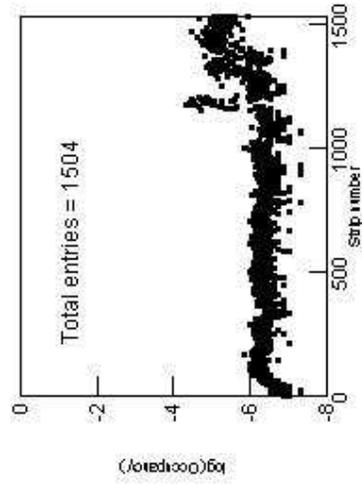
Noise occupancy for layerY3



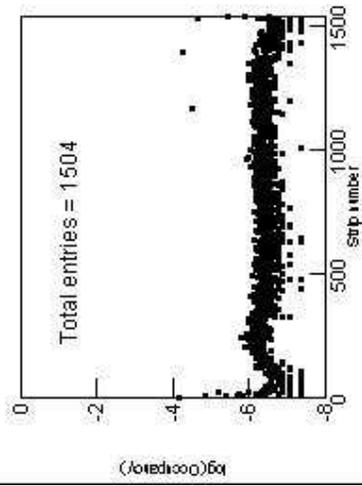
Noise occupancy for layerX1



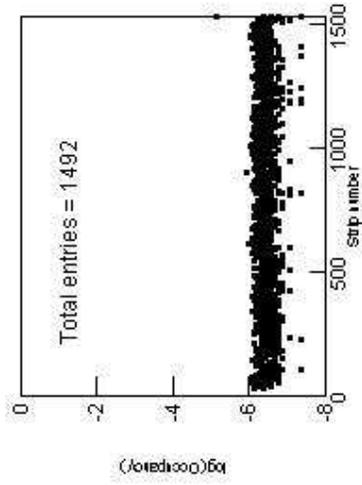
Noise occupancy for layerX2



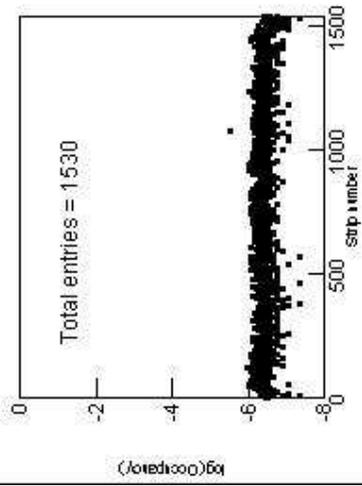
Noise occupancy for layerX3



Noise occupancy for layerY1



Noise occupancy for layerY2



Noise occupancy for layerY3

